



Accredited Laboratory

A2LA has accredited

LAW CALIBRATION, LLC

Saco, ME

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCSL Z540-1-1994 and R205 – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 17th day of May 2024

A blue ink signature of Trace McInturff, written over a horizontal line.

Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 2398.01
Valid to February 28, 2026
Revised: July 26, 2024

For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017
& ANSI/NCSL Z540-1-1994

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CALIBRATION

Valid To: February 28, 2026

Certificate Number: 2398.01

In recognition of the successful completion of the A2LA evaluation process (including an assessment of the organization's compliance with A2LA's Calibration Program Requirements), accreditation is granted to this laboratory to perform the following calibrations^{1, 7}:

I. Chemical

Parameter/Equipment	Range	CMC ² (±)	Comments
pH Meters ³	4 to 10 pH	0.02 pH	Buffer solutions
Conductivity Meters ³	1 µS 10 µS 100 µS 1000 µS 10,000 µS	0.7 µS 0.7 µS 2.3 µS 5.1 µS 47 µS	Conductivity solutions

II. Dimensional

Parameter/Equipment	Range	CMC ² (±)	Comments
Calipers ³	Up to 1 in (1 to 2) in (2 to 3) in (3 to 4) in (4 to 6) in (6 to 7) in (7 to 8) in	39 µin 40 µin 41 µin 42 µin 44 µin 47 µin 48 µin	Gage blocks, gage block adapter, surface plate

Parameter/Equipment	Range	CMC ² (±)	Comments
Calipers ³ (cont)	(8 to 10) in (10 to 12) in (12 to 16) in (16 to 20) in (20 to 30) in (30 to 40) in	52 μin 56 μin 65 μin 75 μin 110 μin 140 μin	Gage blocks, gage block adapter, surface plate
Dial Indicators ³	Up to 1 in	12 μin	Gage blocks, micrometer head
Test Indicators ³	Up to 1 in	39 μin	Gage blocks
Gage Blocks	(0.05 to 0.4) in (0.4 to 0.9) in (0.9 to 1) in (1 to 2) in (2 to 3) in (3 to 4) in (4 to 5) in (5 to 6) in (6 to 8) in (8 to 10) in (10 to 12) in (12 to 16) in	7.1 μin 8.2 μin 8.8 μin 11 μin 14 μin 17 μin 22 μin 23 μin 30 μin 36 μin 42 μin 54 μin	Gage blocks, comparator, lab master
Height Gages ³	(0.1 to 1) in (1 to 3) in (3 to 4) in (4 to 6) in (6 to 8) in (8 to 10) in (10 to 12) in (12 to 16) in (16 to 20) in (20 to 30) in (30 to 40) in	77 μin 78 μin 79 μin 80 μin 82 μin 84 μin 87 μin 93 μin 100 μin 130 μin 150 μin	Gage blocks, surface plate

Parameter/Equipment	Range	CMC ² (±)	Comments
Micrometers ³	(0.1 to 0.25) in (0.25 to 0.5) in (0.5 to 0.75) in (0.75 to 1) in (1 to 2) in (2 to 3) in (3 to 4) in (4 to 5) in (5 to 6) in (6 to 7) in (7 to 8) in (8 to 10) in (10 to 12) in	8 μin 8.9 μin 9 μin 9.5 μin 11 μin 14 μin 17 μin 22 μin 23 μin 28 μin 29 μin 35 μin 40 μin	Gage blocks, surface plate
Rulers & Tape Measures	Up to 25 ft	0.020 in	Gage blocks
Optical Comparators ³ – X & Y	Up to 5 in (6 to 12) in	93 μin 200 μin	Glass standard
Microscopes ³ – X & Y	Up to 1 in	54 μin	Stage micrometer

III. Electrical – DC/Low Frequency

Parameter/Range	Frequency	CMC ^{2, 4} (±)	Comments
AC Voltage – Generate (0 to 12) mV	(3 to 5) Hz (5 to 10) Hz 10 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz	0.19 % + 7 μV 0.068 % + 7 μV 0.012 % + 6 μV 0.029 % + 6 μV 0.12 % + 15 μV 0.62 % + 30 μV 0.62 % + 30 μV	Fluke 5560A

Parameter/Range	Frequency	CMC ^{2,4} (±)	Comments
AC Voltage – Generate (cont)			Fluke 5560A
(12 to 120) mV	(3 to 5) Hz (5 to 10) Hz 10 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz	0.19 % + 7 μV 0.068 % + 7 μV 0.011 % + 6 μV 0.027 % + 8 μV 0.062 % + 20 μV 0.16 % + 30 μV 0.16 % + 30 μV	
120 mV to 1.2 V	(3 to 5) Hz (5 to 10) Hz 10 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz	0.19 % + 75 μV 0.068 % + 70 μV 0.011 % + 60 μV 0.023 % + 14 μV 0.054 % + 40 μV 0.15 % + 80 μV 0.15 % + 80 μV	
(1.2 to 12) V	(3 to 5) Hz 5 to 10) Hz 10 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz	0.19 % + 750 μV 0.068 % + 750 μV 0.011 % + 350 μV 0.023 % + 50 μV 0.054 % + 13 μV 0.16 % + 600 μV 0.16 % + 600 μV	
(12 to 120) V	(3 to 5) Hz (5 to 10) Hz 10 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.19 % + 7.5 mV 0.068 % + 7.5 mV 0.011 % + 3.5 mV 0.023 % + 500 μV 0.054 % + 1.3 mV 0.16 % + 20 mV	
(120 to 330) V	(3 to 5) Hz (5 to 10) Hz 10 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz	0.19 % + 75 mV 0.068 % + 75 mV 0.011 % + 8 mV 0.023 % + 8 mV 0.12 % + 13 mV	
(330 to 1020) V	(33 to 5) Hz (5 to 10) Hz 10 Hz to 10 kHz	0.19 % + 75 mV 0.068 % + 75 mV 0.011 % + 80 mV	

Parameter/Range	Frequency	CMC ^{2,4} (±)	Comments
AC Voltage – Measure			Fluke 8588A
(0 to 10) mV	(1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (300 to 1000) kHz	0.025 % + 1.1 μV 0.037 % + 1.1 μV 0.034 % + 1.1 μV 0.3 % + 1.1 μV 1 % + 4 μV 2 % + 4 μV	
(10 to 100) mV	(1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (300 to 1000) kHz (1 to 2) MHz (2 to 4) MHz (4 to 8) MHz (8 to 10) MHz	0.0068 % + 0.5 μV 0.011 % + 0.5 μV 0.021 % + 1 μV 0.051 % + 5 μV 0.2 % + 30 μV 1 % + 100 μV 1.5 % + 500 μV 4 % + 1 mV 8 % + 1 mV 15 % + 1 mV	
(.1 to 1) V	(1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (300 to 1000) kHz (1 to 2) MHz (2 to 4) MHz (4 to 8) MHz (8 to 10) MHz	0.0064 % + 5 μV 0.011 % + 5 μV 0.021 % + 10 μV 0.051 % + 50 μV 0.2 % + 300 μV 1 % + 1 mV 1.5 % + 5 mV 4 % + 10 mV 8 % + 10 mV 15 % + 10 mV	
(1 to 10) V	(1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (300 to 1000) kHz (1 to 2) MHz (2 to 4) MHz (4 to 8) MHz (8 to 10) MHz	0.0064 % + 50 μV 0.011 % + 50 μV 0.021 % + 100 μV 0.051 % + 500 μV 0.2 % + 3 mV 1 % + 10 mV 1.5 % + 50 mV 4 % + 100 mV 8 % + 100 mV 15 % + 100 mV	
(10 to 100) V	(1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (300 to 1000) kHz	0.007 % + 500 μV 0.009 % + 500 μV 0.021 % + 1 mV 0.051 % + 5 mV 0.35 % + 50 mV 1 % + 500 mV	

Parameter/Equipment	Frequency	CMC ^{2,4} (±)	Comments
AC Voltage – Measure (cont) (100 to 1050) V	1 to 2000) Hz 2 to 10) kHz 10 to 30) kHz 30 to 100) kHz	0.009 % + 25 mV 0.009 % + 25 mV 0.021 % + 25 mV 0.051 % + 100 mV	Fluke 8588A
AC Current – Generate (0 to 120) µA (120 to 1.2) mA (1.2 to 12) mA (12 to 120) mA 120 mA to 1.2 A (1.2 to 3.1) A (3.1 to 12) A	(3 to 45) Hz (45 to 1000) Hz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (3 to 45) Hz (45 to 1000) Hz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (3 to 45) Hz (45 to 1000) Hz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (3 to 45) Hz (45 to 1000) Hz (1 to 5) kHz (5 to 10) kHz (3 to 45) Hz (45 to 1000) Hz (1 to 5) kHz (5 to 10) kHz	0.019 % + 10 nA 0.019 % + 10 nA 0.019 % + 10 nA 0.12 % + 40 nA 0.39 % + 1 µA 0.019 % + 100 nA 0.019 % + 100 nA 0.019 % + 100 nA 0.12 % + 100 nA 0.39 % + 5 µA 0.019 % + 1 µA 0.019 % + 1 µA 0.019 % + 1 µA 0.12 % + 1 µA 0.39 % + 10 µA 0.019 % + 10 µA 0.019 % + 5 µA 0.019 % + 8 µA 0.12 % + 10 µA 0.39 % + 100 µA 0.019 % + 100 µA 0.019 % + 50 µA 0.019 % + 80 µA 0.12 % + 300 µA 0.39 % + 300 µA 0.029 % + 500 µA 0.023 % + 300 µA 0.029 % + 300 µA 0.19 % + 500 µA 0.029 % + 1 mA 0.023 % + 500 µA 0.029 % + 800 µA 0.19 % + 1 mA	Fluke 5560A

Parameter/Equipment	Frequency	CMC ^{2,4} (±)	Comments
AC Current – Generate (cont) (12 to 30.2) A	 (3 to 45) Hz (45 to 1000) Hz (1 to 5) kHz	 0.078 % + 10 mA 0.054 % + 8 mA 0.39 % + 8 mA	Fluke 5560A
AC Current – Measure (0-10) µA (10 to 100) µA (0.1-1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A (1 to 10) A (10 to 30) A	 (1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (1 to 2000) Hz (2 to 10) kHz (10 to 30) kHz (1 to 2000) Hz (2 to 10) kHz	 0.2 % + 2.5 nA 0.2 % + 2.5 nA 0.2 % + 2.5 nA 0.26 % + 5 nA 0.51 % + 5 nA 0.072 % + 5 nA 0.4 % + 10 nA 0.26 % + 50 nA 0.51 % + 50 nA 0.072 % + 50 nA 0.4 % + 100 nA 0.26 % + 500 nA 0.51 % + 500 nA 0.072 % + 500 nA 0.4 % + 1 µA 0.26 % + 5 µA 0.5 % + 5 µA 0.07 % + 5 µA 0.26 % + 100 µA 0.51 % + 100 µA 0.071 % + 100 µA 0.08 % + 500 µA 0.08 % + 500 µA 0.08 % + 12 mA 0.12 % + 12 mA	Fluke 8588A

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
DC Voltage – Generate	(0.00 to 120) mV 120 mV to 1.2 V (1.2 to 12) V (12 to 120) V (120 to 1020) V	0.0009 % + 0.8 μV 0.0006 % + 1 μV 0.0006 % + 10 μV 0.0009 % + 100 μV 0.0009 % + 1000 μV	Fluke 5560A
DC Voltage – Measure	(0.01 to 100) mV 100 mV to 1 V (1 to 10) V (10 to 100) V (100 to 1000) V	0.000 52 % + 0.2 μV 0.000 28 % + 0.3 μV 0.000 28 % + 0.5 μV 0.000 41 % + 30 μV 0.000 43 % + 500 μV	Fluke 8588A
DC Current – Generate	(0 to 120) μA 120 μA to 1.2 mA (1.2 to 12) mA (12 to 120) mA 120 mA to 1.2 A (1.2 to 3.1) A (3.1 to 12) A (12 to 30.2) A	0.0097 % + 6 nA 0.0078 % + 15 nA 0.0078 % + 80 nA 0.0078 % + 800 nA 0.012 % + 10 μA 0.82 % + 150 μA 0.023 % + 250 μA 0.078 % + 500 μA	Fluke 5560A
DC Current – Measure	(0 to 10) μA (10 to 100) μA (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A (1 to 10) A (10 to 30) A	0.0024 % + 0.4 nA 0.000 83 % + 0.4 nA 0.000 76 % + 4 nA 0.000 89 % + 40 nA 0.0033 % + 1 μA 0.01 % + 100 μA 0.017 % + 400 μA 0.049 % + 4.4 mA	Fluke 8588A
Resistance – Generate	(0 to 12) Ω (12 to 120) Ω (0.12 to 1.2) kΩ (1.2 to 12) kΩ (12 to 120) kΩ (0.12 to 1.2) MΩ (1.2 to 12) MΩ (12 to 120) MΩ (0.12 to 1.2) GΩ	0.0019 % + 1 mΩ 0.0019 % + 1 mΩ 0.0019 % + 2 mΩ 0.0019 % + 20 mΩ 0.0019 % + 200 mΩ 0.0019 % + 2 Ω 0.0027 % + 30 Ω 0.033 % + 2.5 kΩ 0.31 % + 100 kΩ	Fluke 5560A

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Resistance – Measure	1 Ω 10 Ω 100 Ω 1 kΩ 10 kΩ 100 kΩ 1 MΩ 10 MΩ 100 MΩ 1 GΩ	0.0011 % + 4 μΩ 0.000 81 % + 14 μΩ 0.000 85 % + 50 μΩ 0.000 71 % + 500 μΩ 0.000 72 % + 5 mΩ 0.000 73 % + 50 mΩ 0.000 82 % + 1 Ω 0.0012 % + .01 kΩ 0.015 % + 10 kΩ 0.056 % + 1 MΩ	Fluke 8588A
Capacitance – Generate	(0.2 to 1.2) nF (1.2 to 12) nF (12 to 120) nF (0.12 to 1.2) μF (1.2 to 12) μF (12 to 120) μF (0.12 to 1.2) mF (1.2 to 12) mF (12 to 120) mF	0.09 % + 2 pF 0.09 % + 5 pF 0.1 % + 30 pF 0.1 % + 300 pF 0.1 % + 3 nF 0.12 % + 25 nF 0.19 % + 250 nF 0.19 % + 3 μF 0.39 % + 30 μF	Fluke 5560A
Capacitance – Measure	1 nF 10 nF 100 nF 1 μF 10 μF 100 μF 1 mF 10 mF 100 mF	0.1 % + 1 pF 0.06 % + 2 pF 0.04 % + 10 pF 0.04 % + 100 pF 0.04 % + 1 nF 0.06 % + 10 nF 0.06 % + 0.1 μF 0.07 % + 1 μF 0.07 % + 10 μF	Fluke 8588A
Inductance – Generate	120 μH 1.2 mH 12 mH 120 mH 1.2 H 12 H 120 H	0.16 % + 200 nH 0.09 % + 1 μH 0.09 % + 10 μH 0.09 % + 100 μH 0.12 % + 1 mH 0.16 % + 10 mH 0.19 % + 100 mH	Fluke 8588A

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Electrical Simulation of Thermocouples ³ – Generate/Measure			
Type B	(600 to 800) °C (800 to 1000) °C (1000 to 1550) °C (1550 to 1820) °C	0.34 °C 0.26 °C 0.23 °C 0.26 °C	Fluke 5560A
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1000) °C	0.31 °C 0.11 °C 0.09 °C 0.12 °C 0.16 °C	
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.19 °C 0.1 °C 0.09 °C 0.11 °C 0.16 °C	
Type K	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1370) °C	0.22 °C 0.1 °C 0.09 °C 0.16 °C 0.27 °C	
Type N	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 410) °C (410 to 1300) °C	0.26 °C 0.12 °C 0.09 °C 0.09 °C 0.16 °C	
Type R	(0 to 250) °C (250 to 400) °C (400 to 1000) °C (1000 to 1760) °C	0.4 °C 0.23 °C 0.22 °C 0.27 °C	
Type S	(0 to 250) °C (250 to 1000) °C (1000 to 1400) °C (1400 to 1760) °C	0.33 °C 0.24 °C 0.26 °C 0.36 °C	
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.47 °C 0.16 °C 0.1 °C 0.09 °C	

IV. Mechanical

Parameter/Equipment	Range	CMC ^{2, 5, 6} (±)	Comments
Electrical Simulation of RTDs ³ –			
PT100 PRT	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.04 °C 0.04 °C 0.05 °C 0.07 °C 0.08 °C 0.09 °C 0.18 °C	Fluke 5560A
PT1000 PRT	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.02 °C 0.02 °C 0.03 °C 0.04 °C 0.05 °C 0.05 °C 0.05 °C 0.18 °C	
Pressure – Measure & Measuring Equipment	(-0.5 to 0.5) in H ₂ O (-25 to 25) mbar (-0.95 to 1) bar (1 to 2.5) bar (2.5 to 40) bar (60 to 110) kPa (-13.5 to 300) psi (300 to 3000) psi (3000 to 10,000) psi (10k to 20k) psi	0.000 76 in H ₂ O 0.015 mbar 0.000 32 bar 0.000 65 bar 0.0098 bar 0.064 kPa 0.074 psi 1.8 psi 2.6 psi 12 psi	Handheld pressure calibrator 20000 psi pressure gauge
Torque Measure - Wrenches	(4 to 50) lbf·in (50 to 500) lbf·in (25 to 250) lbf·ft (250 to 750) lbf·ft (750 to 2000) lbf·ft	0.38 % 0.78 % 0.63 % 0.67 % 0.72 %	AWS torque transducers

Parameter/Equipment	Range	CMC ^{2,6} (\pm)	Comments
Pipettes	(1 to 200) μ L (200 to 500) μ L 500 μ L to 2 mL (2 to 5) mL (5 to 10) mL (10 to 20) mL (20 to 50) mL (50 to 100) mL (100 to 200) mL	0.36 μ L 0.35 μ L 0.4 μ L 1 μ L 2 μ L 4 μ L 10 μ L 20 μ L 40 μ L	Ohaus balances – gravimetric method
Mass – Measure	(1 to 20) mg (20 to 50) mg (50 to 100) mg (100 to 200) mg (200 to 500) mg 500 mg to 1 g (1 to 5) g (5 to 10) g (10 to 20) g (20 to 50) g (50 to 100) g (100 to 200) g (200 to 500) g (500 to 1000) g (1000 to 2000) g (2000 to 5000) g (5000 to 10 000) g (10 000 to 20 000) g (20 000 to 30 000) g (30 000 to 40 000) g (40 000 to 50 000) g	0.005 mg 0.006 mg 0.007 mg 0.008 mg 0.011 mg 0.013 mg 0.017 mg 0.031 mg 0.06 mg 0.11 mg 0.5 mg 1 mg 2.5 mg 5 mg 10 mg 27 mg 51 mg 120 mg 160 mg 230 mg 280 mg	OIML Class E1 ASTM Class 1
Balances & Scales ³	(1 to 20) mg (20 to 50) mg (50 to 100) mg (100 to 200) mg (200 to 500) mg 500 mg to 1 g (1 to 2) g (2 to 5) g (5 to 10) g (10 to 20) g (20 to 50) g (50 to 100) g (100 to 200) g	0.004 mg 0.005 mg 0.006 mg 0.007 mg 0.01 mg 0.015 mg 0.037 mg 0.045 mg 0.06 mg 0.11 mg 0.25 mg 0.5 mg 1 mg	OIML Class E1

Parameter/Equipment	Range	CMC ^{2,6} (\pm)	Comments	
Balances & Scales ³ (con)	(100 to 200) g	1 mg	OIML Class E1	
	(200 to 500) g	2.7 mg		
	(500 to 1000) g (1000 to 2000) g	5 mg 10 mg		
	(2000 to 5000) g (5000 to 10 000) g (10 000 to 20 000) g (20 000 to 30 000) g (30 000 to 40 000) g (40 000 to 50 000) g		29 mg	ASTM Class 1
			58 mg	
			130 mg	
			170 mg	
			230 mg	
			310 mg	

V. Thermodynamic

Parameter/Equipment	Range	CMC ^{2,5,6} (\pm)	Comments
Temperature – Measure Equipment	(-189 to -80) °C	0.09 °C	Drywell temperature source w/RTD
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 300) °C	0.17 °C	
	(300 to 400) °C	0.25 °C	
	(400 to 660) °C	0.33 °C	
Relative Humidity – Measuring Equipment Thermohygrometers	(10 to 80) % RH	0.32 % RH	MBW Chilled Mirror
	(80 to 95) % RH	0.36 % RH	
Infrared Thermometer	(-15 to 0) °C	0.53 °C	Fluke 4180
	(0 to 35) °C	1.8 °C	
	(35 to 50) °C	0.88 °C	
	(50 to 100) °C	1.1 °C	
	(100 to 120) °C	1.1 °C	
	(35 to 100) °C	0.73 °C	Fluke 4181 Emissivity 0.95 wavelength (8 to 14) μ m
	(100 to 200) °C	2.0 °C	
	(200 to 350) °C	2.3 °C	
	(350 to 500) °C	2.1 °C	

VI. Time & Frequency

Parameter/Equipment	Range	CMC ^{2, 6} (\pm)	Comments
Frequency – Generate	1 Hz to 2 MHz	0.0082 %	Fluke 5560A
Frequency – Measure	(1 to 100) Hz 100 Hz to 1 kHz (1 to 10) kHz 10 kHz to 1 MHz	2.3 μ Hz/Hz + 17 μ Hz 2.3 μ Hz/Hz + 170 μ Hz 2.3 μ Hz/Hz + 1.7 mHz 2.3 μ Hz/Hz + 1.7 Hz	Multimeter
Stopwatch & Timers	Up to 19.99 s/day	0.033 s/day	Helmut Klein timometer

¹ This laboratory offers commercial calibration service and field calibration service.

² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

³ Field calibration service is available for this calibration. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g., resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.

⁴ The stated measured values are determined using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure or generate the measured value in the ranges indicated. CMCs are expressed as either a specific value that covers the full range or as a percent or fraction of the reading plus a fixed floor specification.

⁵ In the statement of CMC, percentages are percentage of reading, unless otherwise indicated; L is the numerical value of the nominal length of the device measured in inches

⁶ The type of instrument or material being calibrated is defined by the parameter. This indicates the laboratory is capable of calibrating instruments that measure or generate the values in the ranges indicated for the listed measurement parameter.

⁷ This scope meets A2LA's *P112 Flexible Scope Policy*.